

10600148\_CLS.txt  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10600148 on September 14, 2004

Original Classifications

11 209/573  
7 700/121  
4 382/145  
4 702/118  
2 324/760  
2 430/5  
2 439/482

Cross-Reference Classifications

14 257/E23.179  
13 324/765  
11 209/571  
9 324/158.1  
9 700/116  
5 438/14  
5 700/224  
5 702/187  
5 702/82  
4 700/226  
4 702/117  
3 700/108  
3 700/109  
2 209/583  
2 257/E21.525  
2 257/E25.013  
2 324/704  
2 324/754  
2 430/22  
2 430/311  
2 430/394  
2 430/396  
2 438/17  
2 438/691  
2 438/692  
2 700/117  
2 700/215  
2 702/118

Combined Classifications

14 257/E23.179  
14 324/765  
12 209/573  
11 209/571  
9 324/158.1  
9 700/116  
8 700/121  
6 438/14  
6 702/118  
5 382/145  
5 700/224  
5 702/187  
5 702/82  
4 700/226  
4 702/117  
3 700/108  
3 700/109  
2 209/583  
2 257/E21.525

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2 257/E25.013  
2 324/704  
2 324/754  
2 324/760  
2 430/22  
2 430/311  
2 430/394  
2 430/396  
2 430/5  
2 438/17  
2 438/691  
2 438/692  
2 439/482  
2 700/117  
2 700/215

10600148\_CLSTITLES.txt  
Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10600148 on September 14, 2004

14	257/E23.179	(0 OR, 14 XR)	
	Class 257	:	ACTIVE SOLID-STATE DEVICES
	257/E23.176		...For flat cards, e.g., credit cards (EPO)
	257/E23.179		.Marks applied to semiconductor devices or parts, e.g., registration marks, test patterns, alignment structures, wafer maps (EPO)
14	324/765	(1 OR, 13 XR)	
	Class 324	:	ELECTRICITY: MEASURING AND TESTING
	324/500		FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537		.Of individual circuit component or element
	324/765		..Test of semiconductor device
12	209/573	(11 OR, 1 XR)	
	Class 209	:	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509		SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,			ETC.) FOR SORTING ANY ITEMS
	209/552		.Condition responsive means controls separating means
	209/571		..Electrical test sensing property of item
	209/573		...Electrical component tested
11	209/571	(0 OR, 11 XR)	
	Class 209	:	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509		SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,			ETC.) FOR SORTING ANY ITEMS
	209/552		.Condition responsive means controls separating means
	209/571		..Electrical test sensing property of item
9	324/158.1	(0 OR, 9 XR)	
	Class 324	:	ELECTRICITY: MEASURING AND TESTING
	324/158.1		MISCELLANEOUS
9	700/116	(0 OR, 9 XR)	
	Class 700	:	DATA PROCESSING: GENERIC CONTROL SYSTEMS OR SPECIFIC APPLICATIONS
	700/90		SPECIFIC APPLICATION, APPARATUS OR PROCESS
	700/95		.Product assembly or manufacturing
	700/115		..Product tracking (e.g., having product or carrier identification)
	700/116		...Having identification controlled manufacturing operation
8	700/121	(7 OR, 1 XR)	
	Class 700	:	DATA PROCESSING: GENERIC CONTROL SYSTEMS OR SPECIFIC APPLICATIONS
	700/90		SPECIFIC APPLICATION, APPARATUS OR PROCESS
	700/95		.Product assembly or manufacturing
	700/117		..Particular manufactured product or operation
	700/121		...Integrated circuit production or

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semiconductor fabrication

- 6 438/14 (1 OR, 5 XR)  
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS  
438/14 WITH MEASURING OR TESTING
- 6 702/118 (4 OR, 2 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/108 TESTING SYSTEM  
702/117 .Of circuit  
702/118 ..Testing multiple circuits
- 5 382/145 (4 OR, 1 XR)  
Class 382 : IMAGE ANALYSIS  
382/100 APPLICATIONS  
382/141 .Manufacturing or product inspection  
382/145 ..Inspection of semiconductor device or printed  
circuit board
- 5 700/224 (0 OR, 5 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/213 .Article handling  
700/219 ..Associating or disassociating plural articles  
700/223 ...Collating or sorting  
700/224 ....Having an identification code
- 5 702/187 (0 OR, 5 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/127 MEASUREMENT SYSTEM  
702/187 .History logging or time stamping
- 5 702/82 (0 OR, 5 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT  
702/81 .Quality evaluation  
702/82 ..Having judging means (e.g., accept/reject)
- 4 700/226 (0 OR, 4 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/213 .Article handling  
700/225 ..Having an identification code  
700/226 ...Identification code determines article  
destination
- 4 702/117 (0 OR, 4 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/108 TESTING SYSTEM  
702/117 .Of circuit
- 3 700/108 (0 OR, 3 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

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700/95 .Product assembly or manufacturing  
700/108 ..Performance monitoring

3 700/109 (0 OR, 3 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/95 .Product assembly or manufacturing  
700/108 ..Performance monitoring  
700/109 ...Quality control

2 209/583 (0 OR, 2 XR)  
Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS  
209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND  
APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE  
SORTING,  
ETC.) FOR SORTING ANY ITEMS  
209/552 .Condition responsive means controls separating  
means  
209/576 ..Sensing radiant energy reflected, absorbed,  
emitted, or obstructed by item or adjunct thereof  
209/577 ...Infrared, visible light, or ultraviolet  
209/583 ....Reading indicia

2 257/E21.525 (0 OR, 2 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E21.515 .....Involving use of mechanical auxiliary part  
without use of alloying or soldering process, e.g.,  
pressure contacts (EPO)  
257/E21.521 .Testing or measuring during manufacture or  
treatment or reliability measurement, i.e., testing of  
parts followed by no processing which modifies parts as  
such (EPO)  
257/E21.525 ..Procedures, i.e., sequence of activities  
consisting of plurality of measurement and correction,  
marking or sorting steps (EPO)

2 257/E25.013 (0 OR, 2 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E25.001 ASSEMBLIES CONSISTING OF PLURALITY OF  
INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES  
(EPO)  
257/E25.002 .All devices being of same type, e.g.,  
assemblies of rectifier diodes (EPO)  
257/E25.003 ..Devices not having separate containers (EPO)  
257/E25.01 ...Device consisting of plurality of  
semiconductor or other solid state devices or components  
formed in or on common substrate, e.g., integrated  
circuit  
device (EPO)  
257/E25.013 ....Stacked arrangements of devices (EPO)

2 324/704 (0 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES  
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE  
RELATIONSHIPS  
324/649 .Lumped type parameters  
324/691 ..Using resistance or conductance measurement

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324/704 ...With ratio determination

2 324/754 (0 OR, 2 XR)  
 Class 324 : ELECTRICITY: MEASURING AND TESTING  
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
 ELECTRIC COMPONENTS  
 324/537 .Of individual circuit component or element  
 324/754 ..With probe elements

2 324/760 (2 OR, 0 XR)  
 Class 324 : ELECTRICITY: MEASURING AND TESTING  
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
 ELECTRIC COMPONENTS  
 324/537 .Of individual circuit component or element  
 324/754 ..With probe elements  
 324/760 ...With temperature control

2 430/22 (0 OR, 2 XR)  
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,  
 430/22 COMPOSITION, OR PRODUCT THEREOF  
 REGISTRATION OR LAYOUT PROCESS OTHER THAN COLOR  
 PROOFING

2 430/311 (0 OR, 2 XR)  
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,  
 430/269 COMPOSITION, OR PRODUCT THEREOF  
 IMAGING AFFECTING PHYSICAL PROPERTY OF  
 RADIATION SENSITIVE MATERIAL, OR PRODUCING NONPLANAR OR  
 PRINTING SURFACE - PROCESS, COMPOSITION, OR PRODUCT  
 430/311 .Making electrical device

2 430/394 (0 OR, 2 XR)  
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,  
 430/394 COMPOSITION, OR PRODUCT THEREOF  
 PLURAL EXPOSURE STEPS

2 430/396 (0 OR, 2 XR)  
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,  
 430/396 COMPOSITION, OR PRODUCT THEREOF  
 EFFECTING FRONTAL RADIATION MODIFICATION DURING  
 EXPOSURE, E,G., SCREENING, MASKING, STENCILING, ETC.

2 430/5 (2 OR, 0 XR)  
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,  
 430/4 COMPOSITION, OR PRODUCT THEREOF  
 RADIATION MODIFYING PRODUCT OR PROCESS OF  
 MAKING  
 430/5 .Radiation mask

2 438/17 (0 OR, 2 XR)  
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS  
 438/14 WITH MEASURING OR TESTING  
 438/17 .Electrical characteristic sensed

2 438/691 (0 OR, 2 XR)  
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS  
 438/689 CHEMICAL ETCHING  
 438/690 .Combined with the removal of material by  
 nonchemical means (e.g., ablating, abrading, etc.)  
 438/691 ..Combined mechanical and chemical material  
 removal

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- 2 438/692 (0 OR, 2 XR)  
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
  - 438/689 CHEMICAL ETCHING
  - 438/690 .Combined with the removal of material by  
           nonchemical means (e.g., ablating, abrading, etc.)
  - 438/691 ..Combined mechanical and chemical material  
           removal
  - 438/692 ...Simultaneous (e.g., chemical-mechanical  
           polishing, etc.)
  
- 2 439/482 (2 OR, 0 XR)  
 Class 439 : ELECTRICAL CONNECTORS
  - 439/476.1 INCLUDING HANDLE OR DISTINCT MANIPULATING MEANS
  - 439/481 .Randomly manipulated implement
  - 439/482 ..Test probe
  
- 2 700/117 (0 OR, 2 XR)  
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
           SPECIFIC APPLICATIONS
  - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
  - 700/95 .Product assembly or manufacturing
  - 700/117 ..Particular manufactured product or operation
  
- 2 700/215 (0 OR, 2 XR)  
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
           SPECIFIC APPLICATIONS
  - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
  - 700/213 .Article handling
  - 700/214 ..Article storing, retrieval, or arrangement  
           (e.g., warehousing, automated library)
  - 700/215 ...Having an identification code

PLUS Search Results for S/N 10600148, Searched September 14, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	18582	"702"/\$.ccls.	USPAT	OR	ON	2004/09/14 08:21
L2	20	US-4032949-\$.DID. OR US-4455495-\$.DID. OR US-4510673-\$.DID. OR US-4534014-\$.DID. OR US-4667403-\$.DID. OR US-4871963-\$.DID. OR US-4954453-\$.DID. OR US-5003251-\$.DID. OR US-5110754-\$.DID. OR US-5235550-\$.DID. OR US-5253208-\$.DID. OR US-5256562-\$.DID. OR US-5296402-\$.DID. OR US-5345110-\$.DID. OR US-5352945-\$.DID. OR US-5424652-\$.DID. OR US-0542831-\$.DID. OR US-5440240-\$.DID. OR US-5442561-\$.DID. OR US-5477493-\$.DID.	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:22
L3	20	US-5504369-\$.DID. OR US-5516028-\$.DID. OR US-5538141-\$.DID. OR US-5539235-\$.DID. OR US-5563832-\$.DID. OR US-5581510-\$.DID. OR US-5590069-\$.DID. OR US-5600171-\$.DID. OR US-5603412-\$.DID. OR US-5606193-\$.DID. OR US-5617366-\$.DID. OR US-5619469-\$.DID. OR US-5625816-\$.DID. OR US-5642307-\$.DID. OR US-5865319-\$.DID. OR US-5889674-\$.DID. OR US-6055463-\$.DID. OR US-6075216-\$.DID. OR US-6147316-\$.DID. OR US-6148307-\$.DID. OR US-619097B1-\$.DID. OR US-619473B1-\$.DID. OR US-636329B1-\$.DID. OR US-63654282-\$.DID. OR US-636586B1-\$.DID. OR US-652979B1-\$.DID. OR US-66360682-\$.DID. OR US-67035782-\$.DID.	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:22

L4	40	2 or 3	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:43
L5	49	("5915231" "6049624" "6067507" "6208947" "6226394" "6226394" "6363329" "6400840" "6588854" "6594611" "5907492" "6363295" "6553276" "5859803" "5426072" "5844803" "5856923" "5927512" "6100486" "6122563" "6147316" "6180527" "6307171" "6350959" "6365860" "6365861" "6373011" "6427092" "6437271" "6504123" "6703573" "4387946" "6344401" "5497381" "6307755" "5532612" "6060895" "5972798" "6608385" "6641430" "6676438" "6750136" "5726920" "4343878" "4442188" "5898186" "5976899" "5994915" "6072574" "6091249").pn.	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:43